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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	e200z3
Core Size	32-Bit Single-Core
Speed	60MHz
Connectivity	CANbus, EBI/EMI, LINbus, SCI, SPI, UART/USART
Peripherals	DMA, POR, PWM, WDT
Number of I/O	80
Program Memory Size	1.5MB (1.5M x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	94K x 8
Voltage - Supply (Vcc/Vdd)	4.5V ~ 5.25V
Data Converters	A/D 32x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 125°C (TA)
Mounting Type	Surface Mount
Package / Case	144-LQFP
Supplier Device Package	144-LQFP (20x20)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/spc5634mf2mlq60

- Non-maskable interrupt (NMI) input for handling external events that must produce an immediate response, e.g., power down detection. On this device, the NMI input is connected to the Critical Interrupt Input. (May not be recoverable)
- Critical Interrupt input. For external interrupt sources that are higher priority than provided by the Interrupt Controller. (Always recoverable)
- New 'Wait for Interrupt' instruction, to be used with new low power modes
- Reservation instructions for implementing read-modify-write accesses
- Signal processing extension (SPE) APU
  - Operating on all 32 GPRs that are all extended to 64 bits wide
  - Provides a full compliment of vector and scalar integer and floating point arithmetic operations (including integer vector MAC and MUL operations) (SIMD)
  - Provides rich array of extended 64-bit loads and stores to/from extended GPRs
  - Fully code compatible with e200z6 core
- Floating point (FPU)
  - IEEE 754 compatible with software wrapper
  - Scalar single precision in hardware, double precision with software library
  - Conversion instructions between single precision floating point and fixed point
  - Fully code compatible with e200z6 core
- Long cycle time instructions, except for guarded loads, do not increase interrupt latency
- Extensive system development support through Nexus debug port

- Advanced microcontroller bus architecture (AMBA) crossbar switch (XBAR)
  - Three master ports, four slave ports
    - Masters: CPU Instruction bus; CPU Load/store bus (Nexus); eDMA
    - Slave: Flash; SRAM; Peripheral Bridge; calibration EBI
  - 32-bit internal address bus, 64-bit internal data bus
- Enhanced direct memory access (eDMA) controller
  - 32 channels support independent 8-bit, 16-bit, or 32-bit single value or block transfers
  - Supports variable sized queues and circular queues
  - Source and destination address registers are independently configured to post-increment or remain constant
  - Each transfer is initiated by a peripheral, CPU, or eDMA channel request
  - Each eDMA channel can optionally send an interrupt request to the CPU on completion of a single value or block transfer
- Interrupt controller (INTC)
  - 191 peripheral interrupt request sources
  - 8 software setable interrupt request sources
  - 9-bit vector
    - Unique vector for each interrupt request source
    - Provided by hardware connection to processor or read from register
  - Each interrupt source can be programmed to one of 16 priorities
  - Preemption
    - Preemptive prioritized interrupt requests to processor
    - ISR at a higher priority preempts ISRs or tasks at lower priorities
    - Automatic pushing or popping of preempted priority to or from a LIFO
    - Ability to modify the ISR or task priority. Modifying the priority can be used to implement the Priority Ceiling Protocol for accessing shared resources.
  - Low latency—three clocks from receipt of interrupt request from peripheral to interrupt request to processor

- Enabled out of reset

- Enhanced modular I/O system (eMIOS)
  - 16 timer channels (up to 14 channels in 144 LQFP)
  - 24-bit timer resolution
  - Supports a subset of the timer modes found in eMIOS on MPC5554
  - 3 selectable time bases plus shared time or angle counter bus from eTPU2
  - DMA and interrupt request support
  - Motor control capability
- Second-generation enhanced time processor unit (eTPU2)
  - Object-code compatible with eTPU—no changes are required to hardware or software if only eTPU features are used
  - Intelligent co-processor designed for timing control
  - High level tools, assembler and compiler available
  - 32 channels (each channel has dedicated I/O pin in all packages)
  - 24-bit timer resolution
  - 14 KB code memory and 3 KB data memory
  - Double match and capture on all channels
  - Angle clock hardware support
  - Shared time or angle counter bus with eMIOS
  - DMA and interrupt request support
  - Nexus Class 1 debug support
  - eTPU2 enhancements
    - Counters and channels can run at full system clock speed
    - Software watchdog
    - Real-time performance monitor
    - Instruction set enhancements for smaller more flexible code generation
    - Programmable channel mode for customization of channel operation
- Enhanced queued A/D converter (eQADC)
  - Two independent on-chip redundant signed digit (RSD) cyclic ADCs
    - 8-, 10-, and 12-bit resolution
    - Differential conversions
    - Targets up to 10-bit accuracy at 500 KSample/s (ADC_CLK = 7.5 MHz) and 8-bit accuracy at 1 MSample/s (ADC_CLK = 15 MHz) for differential conversions
    - Differential channels include variable gain amplifier (VGA) for improved dynamic range (×1; ×2; ×4)
    - Differential channels include programmable pull-up and pull-down resistors for biasing and sensor diagnostics (200 kΩ; 100 kΩ; low value of 5 kΩ)
    - Single-ended signal range from 0 to 5 V
    - Sample times of 2 (default), 8, 64 or 128 ADC clock cycles
    - Provides time stamp information when requested
    - Parallel interface to eQADC command FIFOs (CFIFOs) and result FIFOs (RFIFOs)
    - Supports both right-justified unsigned and signed formats for conversion results
    - Temperature sensor to enable measurement of die temperature
    - Ability to measure all power supply pins directly
  - Automatic application of ADC calibration constants
    - Provision of reference voltages (25% VREF and 75% VREF) for ADC calibration purposes
  - Up to 34[1] input channels available to the two on-chip ADCs

Branch Address adder to minimize delays during change of flow operations. Sequential prefetching is performed to ensure a supply of instructions into the execution pipeline. Branch target prefetching is performed to accelerate taken branches. Prefetched instructions are placed into an instruction buffer capable of holding six instructions.

Branches can also be decoded at the instruction buffer and branch target addresses calculated prior to the branch reaching the instruction decode stage, allowing the branch target to be prefetched early. When a branch is detected at the instruction buffer, a prediction may be made on whether the branch is taken or not. If the branch is predicted to be taken, a target fetch is initiated and its target instructions are placed in the instruction buffer following the branch instruction. Many branches take zero cycle to execute by using branch folding. Branches are folded out from the instruction execution pipe whenever possible. These include unconditional branches and conditional branches with condition codes that can be resolved early.

Conditional branches which are not taken and not folded execute in a single clock. Branches with successful target prefetching which are not folded have an effective execution time of one clock. All other taken branches have an execution time of two clocks. Memory load and store operations are provided for byte, halfword, and word (32-bit) data with automatic zero or sign extension of byte and halfword load data as well as optional byte reversal of data. These instructions can be pipelined to allow effective single cycle throughput. Load and store multiple word instructions allow low overhead context save and restore operations. The load/store unit contains a dedicated effective address adder to allow effective address generation to be optimized. Also, a load-to-use dependency does not incur any pipeline bubbles for most cases.

The Condition Register unit supports the condition register (CR) and condition register operations defined by the Power Architecture. The condition register consists of eight 4-bit fields that reflect the results of certain operations, such as move, integer and floating-point compare, arithmetic, and logical instructions, and provide a mechanism for testing and branching. Vectored and autovectored interrupts are supported by the CPU. Vectored interrupt support is provided to allow multiple interrupt sources to have unique interrupt handlers invoked with no software overhead.

The hardware floating-point unit utilizes the IEEE-754 single-precision floating-point format and supports single-precision floating-point operations in a pipelined fashion. The general purpose register file is used for source and destination operands, thus there is a unified storage model for single-precision floating-point data types of 32 bits and the normal integer type. Single-cycle floating-point add, subtract, multiply, compare, and conversion operations are provided. Divide instructions are multi-cycle and are not pipelined.

The Signal Processing Extension (SPE) Auxiliary Processing Unit (APU) provides hardware SIMD operations and supports a full complement of dual integer arithmetic operation including Multiply Accumulate (MAC) and dual integer multiply (MUL) in a pipelined fashion. The general purpose register file is enhanced such that all 32 of the GPRs are extended to 64 bits wide and are used for source and destination operands, thus there is a unified storage model for 32×32 MAC operations which generate greater than 32-bit results.

The majority of both scalar and vector operations (including MAC and MUL) are executed in a single clock cycle. Both scalar and vector divides take multiple clocks. The SPE APU also provides extended load and store operations to support the transfer of data to and from the extended 64-bit GPRs. This SPE APU is fully binary compatible with e200z6 SPE APU used in MPC5554 and MPC5553.

The CPU includes support for Variable Length Encoding (VLE) instruction enhancements. This enables the classic Power Architecture instruction set to be represented by a modified instruction set made up from a mixture of 16- and 32-bit instructions. This results in a significantly smaller code size footprint without noticeably affecting performance. The Power Architecture instruction set and VLE instruction set are available concurrently. Regions of the memory map are designated as PPC or VLE using an additional configuration bit in each of Table Look-aside Buffers (TLB) entries in the MMU.

The CPU core is enhanced by the addition of two additional interrupt sources; Non-Maskable Interrupt and Critical Interrupt. These two sources are routed directly from package pins, via edge detection logic in the SIU to the CPU, bypassing completely the Interrupt Controller. Once the edge detection logic is programmed, it cannot be disabled, except by reset. The non-maskable Interrupt is, as the name suggests, completely un-maskable and when asserted will always result in the immediate execution of the respective interrupt service routine. The non-maskable interrupt is not guaranteed to be recoverable. The Critical Interrupt is very similar to the non-maskable interrupt, but it can be masked by other exceptional interrupts in the CPU and is guaranteed to be recoverable (code execution may be resumed from where it stopped).

intervention. Consequently, for each timer event, the host CPU setup and service times are minimized or eliminated. A powerful timer subsystem is formed by combining the eTPU2 with its own instruction and data RAM. High-level assembler/compiler and documentation allows customers to develop their own functions on the eTPU2.

The eTPU2 includes these distinctive features:

- The Timer Counter (TCR1), channel logic and digital filters (both channel and the external timer clock input [TCRCLK]) now have an option to run at full system clock speed or system clock / 2.
- Channels support unordered transitions: transition 2 can now be detected before transition 1. Related to this enhancement, the transition detection latches (TDL1 and TDL2) can now be independently negated by microcode.
- A new User Programmable Channel Mode has been added: the blocking, enabling, service request and capture characteristics of this channel mode can be programmed via microcode.
- Microinstructions now provide an option to issue Interrupt and Data Transfer requests selected by channel. They can also be requested simultaneously at the same instruction.
- Channel Flags 0 and 1 can now be tested for branching, in addition to selecting the entry point.
- Channel digital filters can be bypassed.
- The Timer Counter (TCR1), channel logic and digital filters (both channel and the external timer clock input [TCRCLK]) now have an option to run at full system clock speed or system clock / 2.
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- A new User Programmable Channel Mode has been added: the blocking, enabling, service request and capture characteristics of this channel mode can be programmed via microcode.
- Microinstructions now provide an option to issue Interrupt and Data Transfer requests selected by channel. They can also be requested simultaneously at the same instruction.
- Channel Flags 0 and 1 can now be tested for branching, in addition to selecting the entry point.
- Channel digital filters can be bypassed.
- 32 channels, each channel is associated with one input and one output signal
  - Enhanced input digital filters on the input pins for improved noise immunity.
  - Identical, orthogonal channels: each channel can perform any time function. Each time function can be assigned to more than one channel at a given time, so each signal can have any functionality.
  - Each channel has an event mechanism which supports single and double action functionality in various combinations. It includes two 24-bit capture registers, two 24-bit match registers, 24-bit greater-equal and equal-only comparators
  - Input and output signal states visible from the host
- 2 independent 24-bit time bases for channel synchronization:
  - First time base clocked by system clock with programmable prescale division from 2 to 512 (in steps of 2), or by output of second time base prescaler
  - Second time base counter can work as a continuous angle counter, enabling angle based applications to match angle instead of time
  - Both time bases can be exported to the eMIOS timer module
  - Both time bases visible from the host
- Event-triggered microengine:
  - Fixed-length instruction execution in two-system-clock microcycle
  - 14 KB of code memory (SCM)
  - 3 KB of parameter (data) RAM (SPRAM)
  - Parallel execution of data memory, ALU, channel control and flow control sub-instructions in selected combinations

- Selectable backwards compatibility with previous FlexCAN versions
- Programmable clock source to the CAN Protocol Interface, either system clock or oscillator clock
- Listen only mode capability
- Programmable loop-back mode supporting self-test operation
- 3 programmable Mask Registers
- Programmable transmit-first scheme: lowest ID, lowest buffer number or highest priority
- Time Stamp based on 16-bit free-running timer
- Global network time, synchronized by a specific message
- Maskable interrupts
- Warning interrupts when the Rx and Tx Error Counters reach 96
- Independent of the transmission medium (an external transceiver is assumed)
- Multi master concept
- High immunity to EMI
- Short latency time due to an arbitration scheme for high-priority messages
- Low power mode, with programmable wake-up on bus activity

2.2.18 System timers

The system timers provide two distinct types of system timer:

- Periodic interrupts/triggers using the Periodic Interrupt Timer (PIT)
- Operating system task monitors using the System Timer Module (STM)

2.2.18.1 Periodic Interrupt Timer (PIT)

The PIT provides five independent timer channels, capable of producing periodic interrupts and periodic triggers. The PIT has no external input or output pins and is intended to be used to provide system ‘tick’ signals to the operating system, as well as periodic triggers for eQADC queues. Of the five channels in the PIT, four are clocked by the system clock, one is clocked by the crystal clock. This one channel is also referred to as Real Time Interrupt (RTI) and is used to wakeup the device from low power stop mode.

The following features are implemented in the PIT:

- 5 independent timer channels
- Each channel includes 32-bit wide down counter with automatic reload
- 4 channels clocked from system clock
- 1 channel clocked from crystal clock (wake-up timer)
- Wake-up timer remains active when System STOP mode is entered. Used to restart system clock after predefined timeout period
- Each channel can optionally generate an interrupt request or a trigger event (to trigger eQADC queues) when the timer reaches zero

2.2.18.2 System Timer Module (STM)

The System Timer Module (STM) is designed to implement the software task monitor as defined by AUTOSAR (see http://www.autosar.org). It consists of a single 32-bit counter, clocked by the system clock, and four independent timer comparators. These comparators produce a CPU interrupt when the timer exceeds the programmed value.

The following features are implemented in the STM:

- One 32-bit up counter with 8-bit prescaler
- Four 32-bit compare channels

Table 4. Signal details (continued)

Signal	Module or Function	Description
CAL_RD_$\overline{WR}$	Calibration Bus	RD_$\overline{WR}$ indicates whether the current transaction is a read access or a write access.
CAL_$\overline{TS}$_ALE	Calibration Bus	The Transfer Start signal ($\overline{TS}$) is asserted by the MPC5634M to indicate the start of a transfer. The Address Latch Enable (ALE) signal is used to demultiplex the address from the data bus.
CAL_$\overline{EVTO}$	Calibration Bus	Nexus Event Out
CAL_MCKO	Calibration Bus	Nexus Message Clock Out
NEXUSCFG	Nexus/Calibration Bus	Nexus/Calibration Bus selector
eMIOS[0:23]	eMIOS	eMIOS I/O channels
AN[0:39]	eQADC	Single-ended analog inputs for analog-to-digital converter
FCK	eQADC	eQADC free running clock for eQADC SSI.
MA[0:2]	eQADC	These three control bits are output to enable the selection for an external Analog Mux for expansion channels.
REFBYPC	eQADC	Bypass capacitor input
SDI	eQADC	Serial data in
SDO	eQADC	Serial data out
SDS	eQADC	Serial data select
VRH	eQADC	Voltage reference high input
VRL	eQADC	Voltage reference low input
SCI_A_RX SCI_B_RX	eSCI_A – eSCI_B	eSCI receive
SCI_A_TX SCI_B_TX	eSCI_A – eSCI_B	eSCI transmit
ETPU_A[0:31]	eTPU	eTPU I/O channel
CAN_A_TX CAN_C_TX	FlexCan_A – FlexCAN_C	FlexCAN transmit
CAN_A_RX CAN_C_RX	FlexCAN_A – FlexCAN_C	FlexCAN receive
JCOMP	JTAG	Enables the JTAG TAP controller.
TCK	JTAG	Clock input for the on-chip test and debug logic.
TDI	JTAG	Serial test instruction and data input for the on-chip test and debug logic.
TDO	JTAG	Serial test data output for the on-chip test logic.
TMS	JTAG	Controls test mode operations for the on-chip test and debug logic.

Table 14. PMC electrical characteristics (continued)

ID	Name		C	Parameter	Min	Typ	Max	Unit	Notes
1d	—	CC	C	Bandgap reference supply voltage variation	—	3000	—	ppm /V	
2	Vdd	CC	C	Nominal VDD core supply internal regulator target DC output voltage[2]	—	1.28	—	V	
2a	—	CC	P	Nominal VDD core supply internal regulator target DC output voltage variation at power-on reset	Vdd – 6%	Vdd	Vdd + 10%	V	
2b	—	CC	P	Nominal VDD core supply internal regulator target DC output voltage variation after power-on reset	Vdd – 10[3]	Vdd	Vdd + 3%	V	
2c	—	CC	C	Trimming step Vdd	—	20	—	mV	
2d	Ivrcctl	CC	C	Voltage regulator controller for core supply maximum DC output current	20	—	—	mA	
3	Lvi1p2	CC	C	Nominal LVI for rising core supply[4,5]	—	1.160	—	V	
3a	—	CC	C	Variation of LVI for rising core supply at power-on reset[5,6]	1.120	1.200	1.280	V	
3b	—	CC	C	Variation of LVI for rising core supply after power-on reset[5,6]	Lvi1p2–3%	Lvi1p2	Lvi1p2+3%	V	
3c	—	CC	C	Trimming step LVI core supply[5]	—	20	—	mV	
3d	Lvi1p2_h	CC	C	LVI core supply hysteresis[5]	—	40	—	mV	
4	Por1.2V_r	CC	C	POR 1.2 V rising	—	0.709	—	V	
4a	—	CC	C	POR 1.2 V rising variation	Por1.2V_r– 35%	Por1.2V_r	Por1.2V_r+ 35%	V	
4b	Por1.2V_f	CC	C	POR 1.2 V falling	—	0.638	—	V	
4c	—	CC	C	POR 1.2 V falling variation	Por1.2V_f– 35%	Por1.2V_f	Por1.2V_f+ 35%	V	
5	Vdd33	CC	C	Nominal 3.3 V supply internal regulator DC output voltage	—	3.39	—	V	
5a	—	CC	P	Nominal 3.3 V supply internal regulator DC output voltage variation at power-on reset[6]	Vdd33 – 8.5%	Vdd33	Vdd3 + 7%	V	

Table 14. PMC electrical characteristics (continued)

ID	Name		C	Parameter	Min	Typ	Max	Unit	Notes
5b	—	CC	P	Nominal 3.3 V supply internal regulator DC output voltage variation after power-on reset	Vdd33 – 7.5%	Vdd33	Vdd33 + 7%	V	With internal load up to Idd3p3
5c	—	CC	D	Voltage regulator 3.3 V output impedance at maximum DC load	—	—	2	Ω	
5d	Idd3p3	CC	P	Voltage regulator 3.3 V maximum DC output current	80	—	—	mA	
5e	Vdd33 ILim[6]	CC	C	Voltage regulator 3.3 V DC current limit	—	130	—	mA	
6	Lvi3p3	CC	C	Nominal LVI for rising 3.3 V supply[5]	—	3.090	—	V	The Lvi3p3 specs are also valid for the Vddeh LVI
6a	—	CC	C	Variation of LVI for rising 3.3 V supply at power-on reset[5]	Lvi3p3–6%	Lvi3p3	Lvi3p3+6%	V	See note [7]
6b	—	CC	C	Variation of LVI for rising 3.3 V supply after power-on reset[5]	Lvi3p3–3%	Lvi3p3	Lvi3p3+3%	V	See note 7
6c	—	CC	C	Trimming step LVI 3.3 V[5]	—	20	—	mV	
6d	Lvi3p3_h	CC	C	LVI 3.3 V hysteresis[5]	—	60	—	mV	
7	Por3.3V_r	CC	C	Nominal POR for rising 3.3 V supply	—	2.07	—	V	The 3.3V POR specs are also valid for the Vddeh POR
7a	—	CC	C	Variation of POR for rising 3.3 V supply	Por3.3V_r–35%	Por3.3V_r	Por3.3V_r+35%	V	
7b	Por3.3V_f	CC	C	Nominal POR for falling 3.3 V supply	—	1.95	—	V	
7c	—	CC	C	Variation of POR for falling 3.3 V supply	Por3.3V_f–35%	Por3.3V_f	Por3.3V_f+35%	V	
8	Lvi5p0	CC	C	Nominal LVI for rising 5 V VDDREG supply[5]	—	4.290	—	V	
8a	—	CC	C	Variation of LVI for rising 5 V VDDREG supply at power-on reset[5]	Lvi5p0–6%	Lvi5p0	Lvi5p0+6%	V	
8b	—	CC	C	Variation of LVI for rising 5 V VDDREG supply power-on reset[5]	Lvi5p0–3%	Lvi5p0	Lvi5p0+3%	V	
8c	—	CC	C	Trimming step LVI 5 V[5]	—	20	—	mV	

[8] V_{FLASH} is only available in the calibration package.

[9] Regulator is functional, with derated performance, with supply voltage down to 4.0 V.

[10] Multi-voltage pads (type pad_multv_hv) must be supplied with a power supply between 4.75 V and 5.25 V.

[11] The slew rate (SRC) setting must be 0b11 when in low-swing mode.

[12] While in low-swing mode there are no restrictions in transitioning to high-swing mode.

[13] Pin in low-swing mode can accept a 5 V input.

[14] Values are pending characterization.

[15] Pin in low-swing mode can accept a 5 V input.

[16] Characterization based capability:

IOH_S = {6, 11.6} mA and IOL_S = {9.2, 17.7} mA for {slow, medium} I/O with VDDEH=4.5 V;
IOH_S = {2.8, 5.4} mA and IOL_S = {4.2, 8.1} mA for {slow, medium} I/O with VDDEH=3.0 V

[17] Characterization based capability:

IOH_F = {12, 20, 30, 40} mA and IOL_F = {24, 40, 50, 65} mA for {00, 01,10, 11} drive mode with VDDE=3.0 V;
IOH_F = {7, 13, 18, 25} mA and IOL_F = {18, 30, 35, 50} mA for {00, 01, 10, 11} drive mode with VDDE=2.25 V;
IOH_F = {3, 7, 10, 15} mA and IOL_F = {12, 20, 27, 35} mA for {00, 01, 10, 11} drive mode with VDDE=1.62 V

[18] All VOL/VOH values 100% tested with ± 2 mA load.

[19] Run mode as follows:

System clock = 40/60/80 MHz + FM 2%
Code executed from flash memory
ADC0 at 16 MHz with DMA enabled
ADC1 at 8 MHz
eMIOS pads toggle in PWM mode with a rate between 100 kHz and 500 kHz
eTPU pads toggle in PWM mode with a rate between 10 kHz and 500 kHz
CAN configured for a bit rate of 500 kHz
DSPI configured in master mode with a bit rate of 2 MHz
eSCI transmission configured with a bit rate of 100 kHz

[20] Bypass mode, system clock at 1 MHz (using system clock divider), PLL shut down, CPU running simple executive code, 4 x ADC conversion every 10 ms, 2 × PWM channels at 1 kHz, all other modules stopped.

[21] Bypass mode, system clock at 1 MHz (using system clock divider), CPU stopped, PIT running, all other modules stopped.

[22] When using the internal regulator only, a bypass capacitor should be connected to this pin. External circuits should not be powered by the internal regulator. The internal regulator can be used as a reference for an external debugger.

[23] Power requirements for each I/O segment are dependent on the frequency of operation and load of the I/O pins on a particular I/O segment, and the voltage of the I/O segment. See Table 23 for values to calculate power dissipation for specific operation. The total power consumption of an I/O segment is the sum of the individual power consumptions for each pin on the segment.

[24] Absolute value of current, measured at V_{IL} and V_{IH}.

[25] Weak pull up/down inactive. Measured at V_{DDE} = 3.6 V and V_{DDEH} = 5.25 V. Applies to pad types: fast (pad_fc).

[26] Maximum leakage occurs at maximum operating temperature. Leakage current decreases by approximately one-half for each 8 to 12 ^{o}C, in the ambient temperature range of 50 to 125 ^{o}C. Applies to pad types: pad_a and pad_ae.

[27] Applies to CLKOUT, external bus pins, and Nexus pins.

[28] Applies to the FCK, SDI, SDO, and $\overline{SDS}$ pins.

[29] This programmable option applies only to eQADC differential input channels and is used for biasing and sensor diagnostics.

[30] When the pull-up and pull-down of the same nominal 200 KΩ or 100 KΩ value are both enabled, assuming no interference from external devices, the resulting pad voltage will be 0.5*V_{DDE} ± 2.5%

Table 26. DSPI LVDS pad specification [1, 2] (continued)

12	Diff Skew ltphla-tplhbl or ltplhb-tphlal	T_{SKEW}	CC	D				0.5	ns
Termination									
13	Trans. Line (differential Zo)		CC	D		95	100	105	Ω
14	Temperature		CC	D		–40		150	°C

1 These are typical values that are estimated from simulation.

2 These specifications are subject to change per device characterization.

3 Preliminary target values. Actual specifications to be determined.

4.10 Oscillator and PLLMRFM electrical characteristics

Table 27. PLLMRFM electrical specifications[1]

(V_{DDPLL} =1.14 V to 1.32 V, V_{SS} = V_{SSPLL} = 0 V, T_A = T_L to T_H)

Symbol		C	Parameter		Conditions	Value		Unit
						min	max	
$f_{ref\_crystal}$ f_{ref_ext}	CC	D	PLL reference frequency range[2]		Crystal reference	4	20	MHz
		C			External reference	4	80	
f_{pll_in}	CC	P	Phase detector input frequency range (after pre-divider)		—	4	16	MHz
f_{vco}	CC	P	VCO frequency range[3]		—	256	512	MHz
f_{sys}	CC	C	On-chip PLL frequency[2]		—	16	80	MHz
f_{sys}	CC	T	System frequency in bypass mode[4]		Crystal reference	4	20	MHz
		P			External reference	0	80	
t_{CYC}	CC	D	System clock period		—	—	1 / f_{sys}	ns
f_{LORL} f_{LORH}	CC	D	Loss of reference frequency window[5]		Lower limit	1.6	3.7	MHz
		D			Upper limit	24	56	
f_{SCM}	CC	P	Self-clocked mode frequency [6,7]		—	1.2	75	MHz
C_{JITTER}	CC	T	CLKOUT period jitter[8,9,10,11]	Peak-to-peak (clock edge to clock edge)	f_{SYS} maximum	–5	5	% f_{CLKOUT}
		T		Long-term jitter (avg. over 2 ms interval)		–6	6	ns
t_{cst}	CC	T	Crystal start-up time [12, 13]		—	—	10	ms
V_{IHEXT}	CC	T	EXTAL input high voltage		Crystal Mode[14], 0.8 ≤ Vxtal ≤ 1.5V[15]	Vxtal + 0.4	—	V
		T			External Reference[14, 16]	V_{RC33}/2 + 0.4	V_{RC33}	

Table 34. Pad AC specifications (3.3 V)[1] (continued)

Pad Type		C	Output Delay (ns)[2,3] Low-to-High / High-to-Low		Rise/Fall Edge (ns)[3,4]		Drive Load (pF)	SRC/DSC
			Min	Max	Min	Max		MSB,LSB
Fast	CC	D		2.5/2.5		1.2/1.2	10	00
	CC	D		2.5/2.5		1.2/1.2	20	01
	CC	D		2.5/2.5		1.2/1.2	30	10
	CC	D		2.5/2.5		1.2/1.2	50	11[8]
pad_i_hv[12]	CC	D	0.5/0.5	3/3	0.4/0.4	1.5/1.5	0.5	N/A
pull_hv	CC	D	NA	6000		5000/5000	50	N/A

1 These are worst case values that are estimated from simulation and not tested. The values in the table are simulated at f_{SYS} = 80 MHz, V_{DD} = 1.14 V to 1.32 V, V_{DDE} = 3 V to 3.6 V, V_{DDEH} = 3 V to 3.6 V, $T_A = T_L$ to T_H.

2 This parameter is supplied for reference and is not guaranteed by design and not tested.

3 Delay and rise/fall are measured to 20% or 80% of the respective signal.

4 This parameter is guaranteed by characterization before qualification rather than 100% tested.

5 In high swing mode, high/low swing pad Vol and Voh values are the same as those of the slew controlled output pads

6 Medium Slew-Rate Controlled Output buffer. Contains an input buffer and weak pullup/pulldown.

7 Output delay is shown in Figure 8. Add a maximum of one system clock to the output delay for delay with respect to system clock.

8 Can be used on the tester

9 This drive select value is not supported. If selected, it will be approximately equal to 11.

10 Slow Slew-Rate Controlled Output buffer. Contains an input buffer and weak pullup/pulldown.

11 Slow Slew-Rate Controlled Output buffer. Contains an input buffer and weak pullup/pulldown.

12 Stand alone input buffer. Also has weak pull-up/pull-down.

Table 35. Pad AC specifications (1.8 V)

Pad Type		C	Output Delay (ns)[1,2] Low-to-High / High-to-Low		Rise/Fall Edge (ns)[3]		Drive Load (pF)	SRC/DSC
			Min	Max	Min	Max		MSB,LSB
Fast	CC	D		3.0/3.0	2.0/1.5		10	00
	CC	D		3.0/3.0	2.0/1.5		20	01
	CC	D		3.0/3.0	2.0/1.5		30	10
	CC	D		3.0/3.0	2.0/1.5		50	11[4]

1 This parameter is supplied for reference and is not guaranteed by design and not tested.

2 Delay and rise/fall are measured to 20% or 80% of the respective signal.

3 This parameter is guaranteed by characterization before qualification rather than 100% tested.

4 Can be used on the tester.

Table 36. JTAG pin AC electrical characteristics[1] (continued)

#	Symbol		C	Characteristic	Min. Value	Max. Value	Unit
12	t_{BSDVZ}	CC	D	TCK Falling Edge to Output Valid out of High Impedance	—	50	ns
13	t_{BSDHZ}	CC	D	TCK Falling Edge to Output High Impedance	—	50	ns
14	t_{BSDST}	CC	D	Boundary Scan Input Valid to TCK Rising Edge	50	—	ns
15	t_{BSDHT}	CC	D	TCK Rising Edge to Boundary Scan Input Invalid	50	—	ns

1 JTAG timing specified at V_{DD} = 1.14 V to 1.32 V, V_{DDEH} = 4.5 V to 5.25 V with multi-voltage pads programmed to Low-Swing mode, $T_A = T_L$ to T_H, and C_L = 30 pF with DSC = 0b10, SRC = 0b00. These specifications apply to JTAG boundary scan only. See Table 37 for functional specifications.

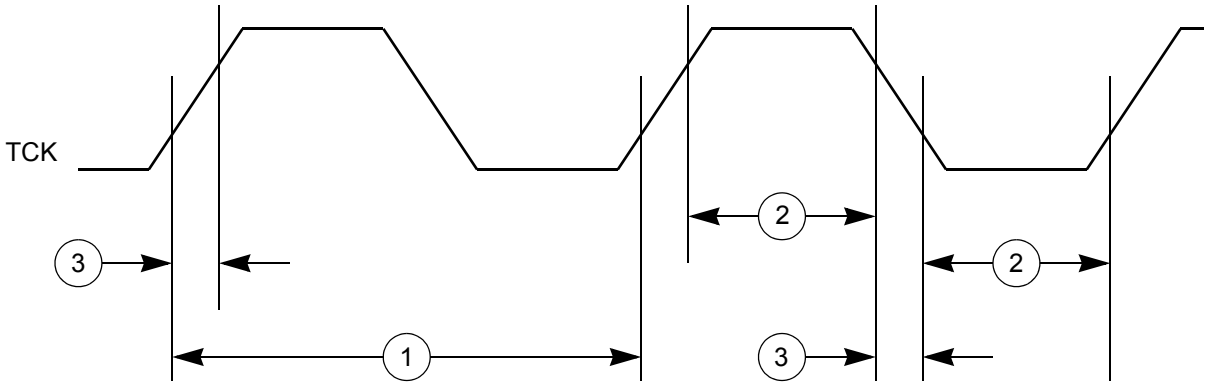


Figure 9. JTAG test clock input timing

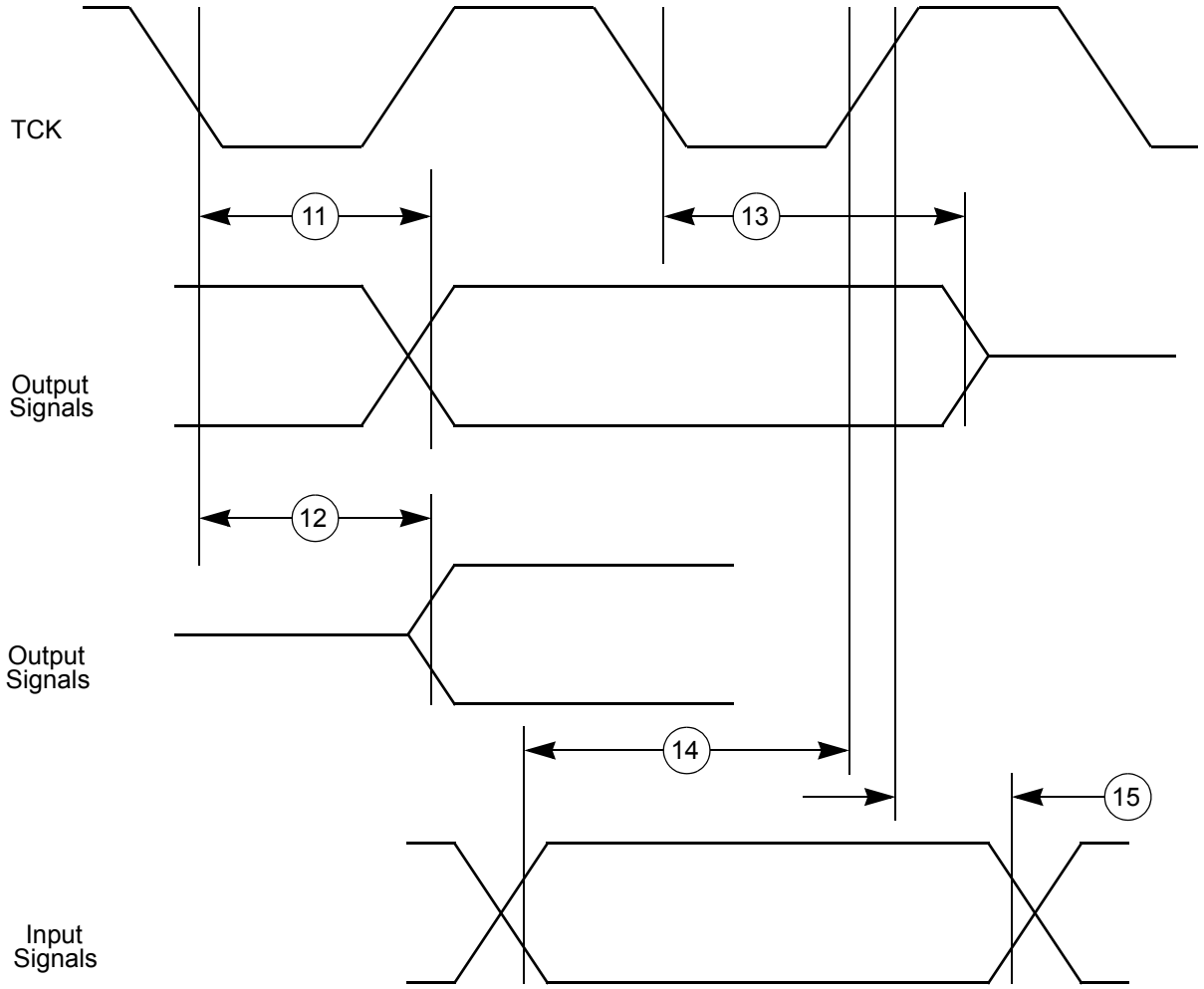


Figure 12. JTAG boundary scan timing

4.16.2 Nexus timing

Table 37. Nexus debug port timing[1]

#	Symbol		C	Characteristic	Min. Value	Max. Value	Unit
1	t_{MCYC}	CC	D	MCKO Cycle Time	$2^{2,3}$	8	t_{CYC}
1a	t_{MCYC}	CC	D	Absolute Minimum MCKO Cycle Time	100[4]	—	ns
2	t_{MDC}	CC	D	MCKO Duty Cycle	40	60	%
3	t_{MDOV}	CC	D	MCKO Low to MDO Data Valid[5]	– 0.1	0.2	t_{MCYC}
4	t_{MSEOV}	CC	D	MCKO Low to $\overline{\text{MSEO}}$ Data Valid[5]	0.1	0.2	t_{MCYC}
6	t_{EVTOV}	CC	D	MCKO Low to $\overline{\text{EVTO}}$ Data Valid[5]	– 0.1	0.2	t_{MCYC}
7	t_{EVTIPW}	CC	D	$\overline{\text{EVTI}}$ Pulse Width	4.0	—	t_{TCYC}
8	t_{EVTOPW}	CC	D	$\overline{\text{EVTO}}$ Pulse Width	1	—	t_{MCYC}

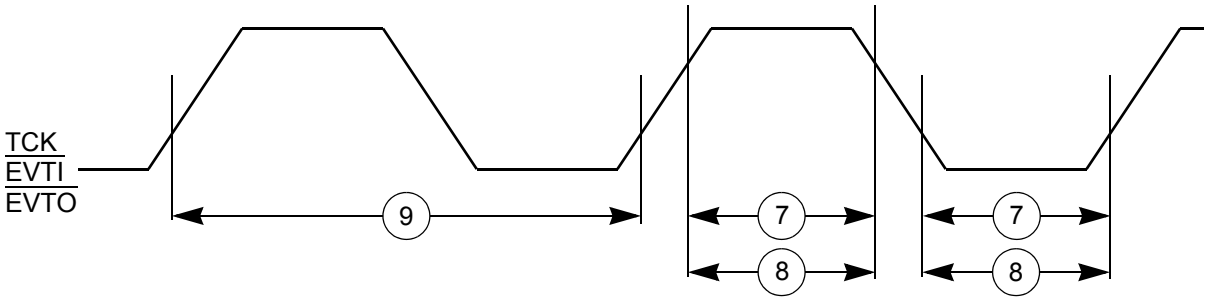


Figure 14. Nexus event trigger and test clock timings

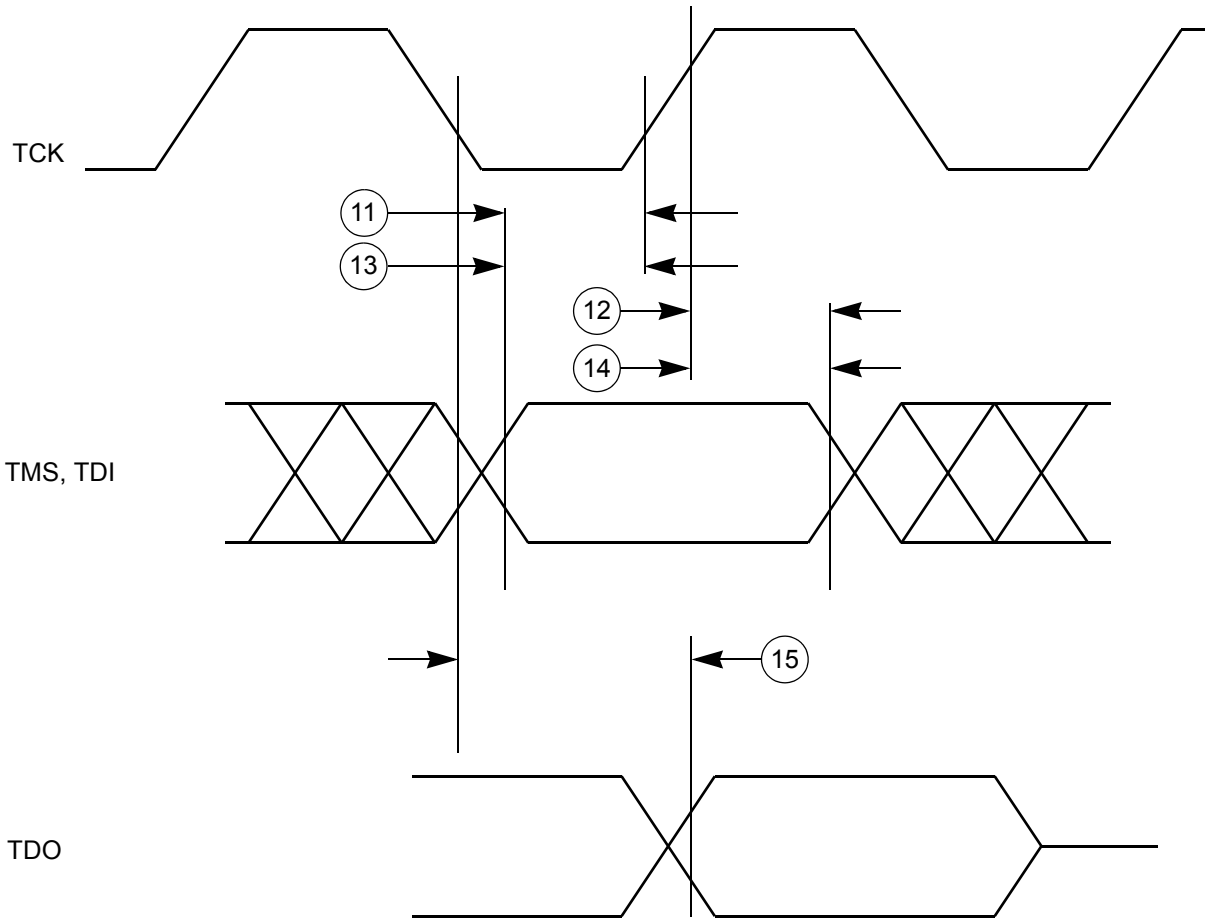


Figure 15. Nexus TDI, TMS, TDO timing

Table 40. DSPI timing[1,2] (continued)

#	Symbol		C	Characteristic	40 MHz		60 MHz		80 MHz		Unit
					Min.	Max.	Min.	Max.	Min.	Max.	
10	t_{HI}	CC	Data Hold Time for Inputs								
			D	Master (MTFE = 0)	–4	—	–4	—	–4	—	ns
			D	Slave	7	—	7	—	7	—	
			D	Master (MTFE = 1, CPHA = 0)[7]	45	—	25	—	21	—	
			D	Master (MTFE = 1, CPHA = 1)	–4	—	–4	—	–4	—	
11	t_{SUO}	CC	Data Valid (after SCK edge)								
			D	Master (MTFE = 0)	—	6	—	6	—	6	ns
			D	Slave	—	25	—	25	—	25	
			D	Master (MTFE = 1, CPHA=0)	—	45	—	25	—	21	
			D	Master (MTFE = 1, CPHA=1)	—	6	—	6	—	6	
12	t_{HO}	CC	Data Hold Time for Outputs								
			D	Master (MTFE = 0)	–5	—	–5	—	–5	—	ns
			D	Slave	5.5	—	5.5	—	5.5	—	
			D	Master (MTFE = 1, CPHA = 0)	8	—	4	—	3	—	
			D	Master (MTFE = 1, CPHA = 1)	–5	—	–5	—	–5	—	

1 All DSPI timing specifications use the fastest slew rate (SRC = 0b11) on pad type M or MH. DSPI signals using pad types of S or SH have an additional delay based on the slew rate. DSPI timing is specified at VDDEH = 3.0–5.25 V, TA = TL to TH, and CL = 50 pF with SRC = 0b11.

2 Speed is the nominal maximum frequency. Max speed is the maximum speed allowed including frequency modulation (FM). 42 MHz parts allow for 40 MHz system clock + 2% FM; 62 MHz parts allow for a 60 MHz system clock + 2% FM, and 82 MHz parts allow for 80 MHz system clock + 2% FM.

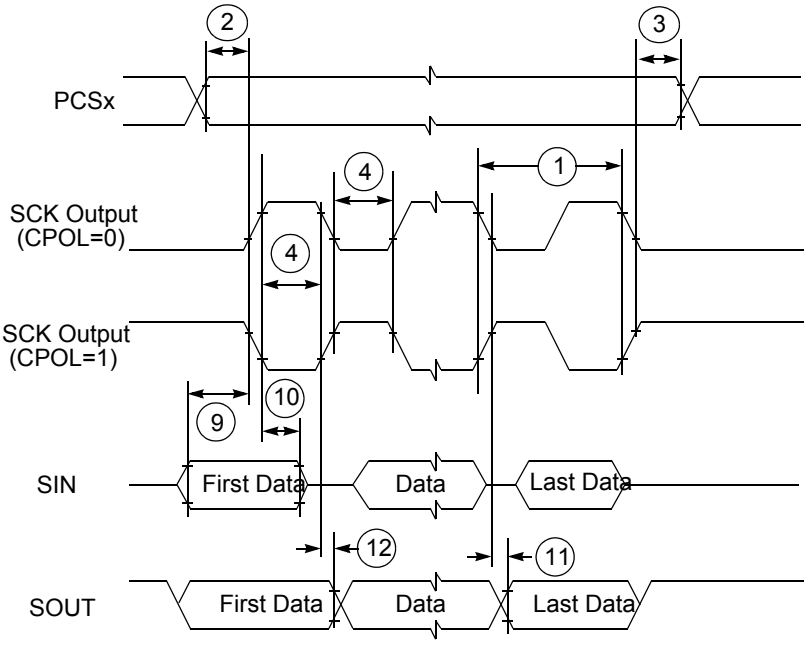
3 The minimum DSPI Cycle Time restricts the baud rate selection for given system clock rate. These numbers are calculated based on two MPC5634M devices communicating over a DSPI link.

4 The actual minimum SCK cycle time is limited by pad performance.

5 The maximum value is programmable in DSPI_CTARx[PSSCK] and DSPI_CTARx[CSSCK].

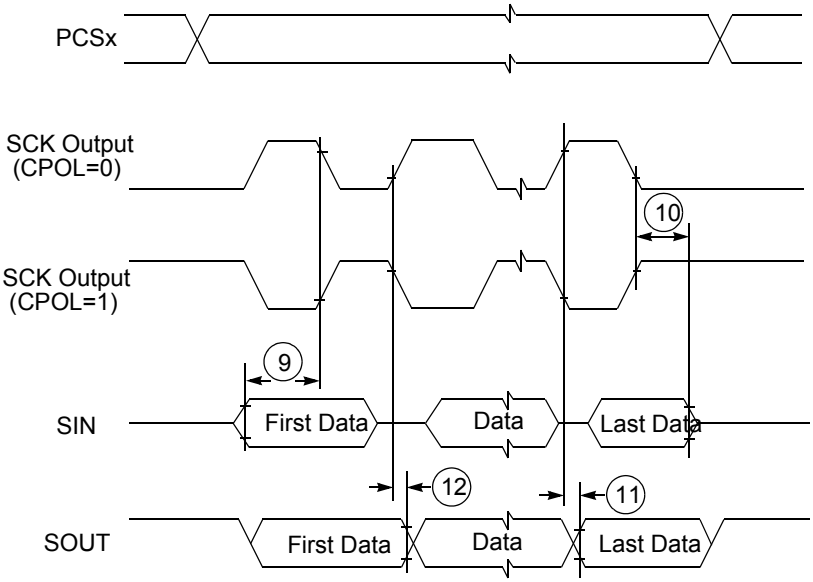
6 The maximum value is programmable in DSPI_CTARx[PASC] and DSPI_CTARx[ASC].

7 This number is calculated assuming the SMPL_PT bitfield in DSPI_MCR is set to 0b10.



These numbers reference Table 40.

Figure 20. DSPI classic SPI timing – master, CPHA = 0



These numbers reference Table 40.

Figure 21. DSPI classic SPI timing – master, CPHA = 1

4.16.6 eQADC SSI timing

Table 41. eQADC SSI timing characteristics (pads at 3.3 V or at 5.0 V)[1]

CLOAD = 25pF on all outputs. Pad drive strength set to maximum.								
#	Symbol		C	Rating	Min	Typ	Max	Unit
1	f_{FCK}	CC	D	FCK Frequency [2, 3]	1/17 f_{SYS_CLK}		1/2 f_{SYS_CLK}	Hertz
1	t_{FCK}	CC	D	FCK Period (t_{FCK} = 1/ f_{FCK})	2 t_{SYS_CLK}		17t_{SYS_CLK}	seconds
2	t_{FCKHT}	CC	D	Clock (FCK) High Time	t_{SYS_CLK} – 6.5		9* t_{SYS_CLK} + 6.5	ns
3	t_{FCKLT}	CC	D	Clock (FCK) Low Time	t_{SYS_CLK} – 6.5		8* t_{SYS_CLK} + 6.5	ns
4	t_{SDS_LL}	CC	D	SDS Lead/Lag Time	–7.5		+7.5	ns
5	t_{SDO_LL}	CC	D	SDO Lead/Lag Time	–7.5		+7.5	ns
6	t_{DVFE}	CC	D	Data Valid from FCK Falling Edge (t_{FCKLT}+t_{SDO_LL})	1			ns
7	t_{EQ_SU}	CC	D	eQADC Data Setup Time (Inputs)	22			ns
8	t_{EQ_HO}	CC	D	eQADC Data Hold Time (Inputs)	1			ns

1 SS timing specified at f_{SYS} = 80 MHz, V_{DD} = 1.14 V to 1.32 V, V_{DDEH} = 4.5 V to 5.25 V, T_A = T_L to T_H, and C_L = 50 pF with SRC = 0b00.

2 Maximum operating frequency is highly dependent on track delays, master pad delays, and slave pad delays.

3 FCK duty is not 50% when it is generated through the division of the system clock by an odd number.

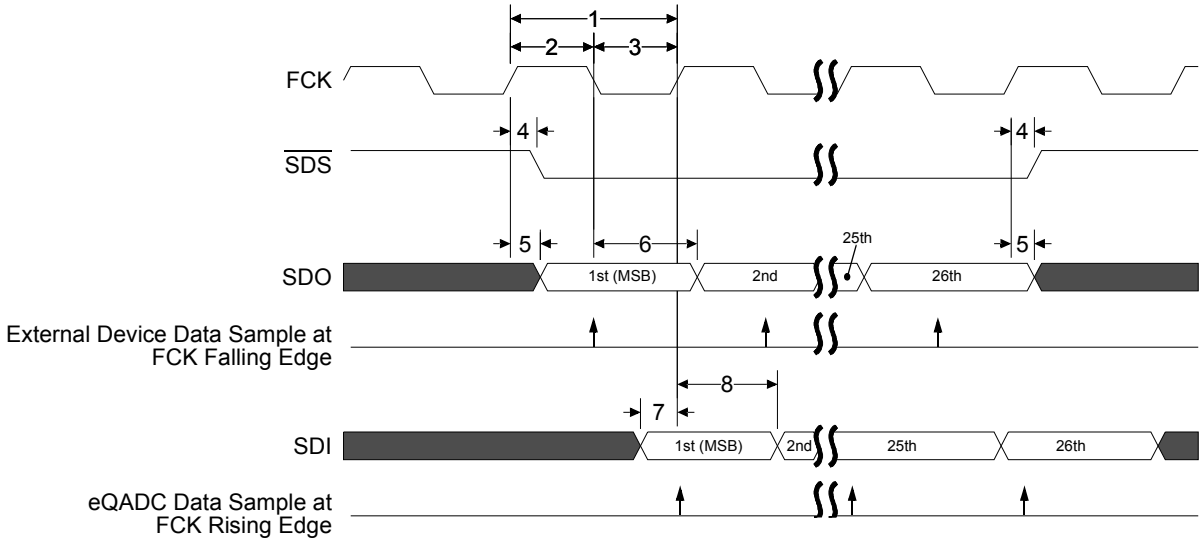


Figure 29. eQADC SSI timing

5 Packages

5.1 Package mechanical data

5.1.1 144 LQFP

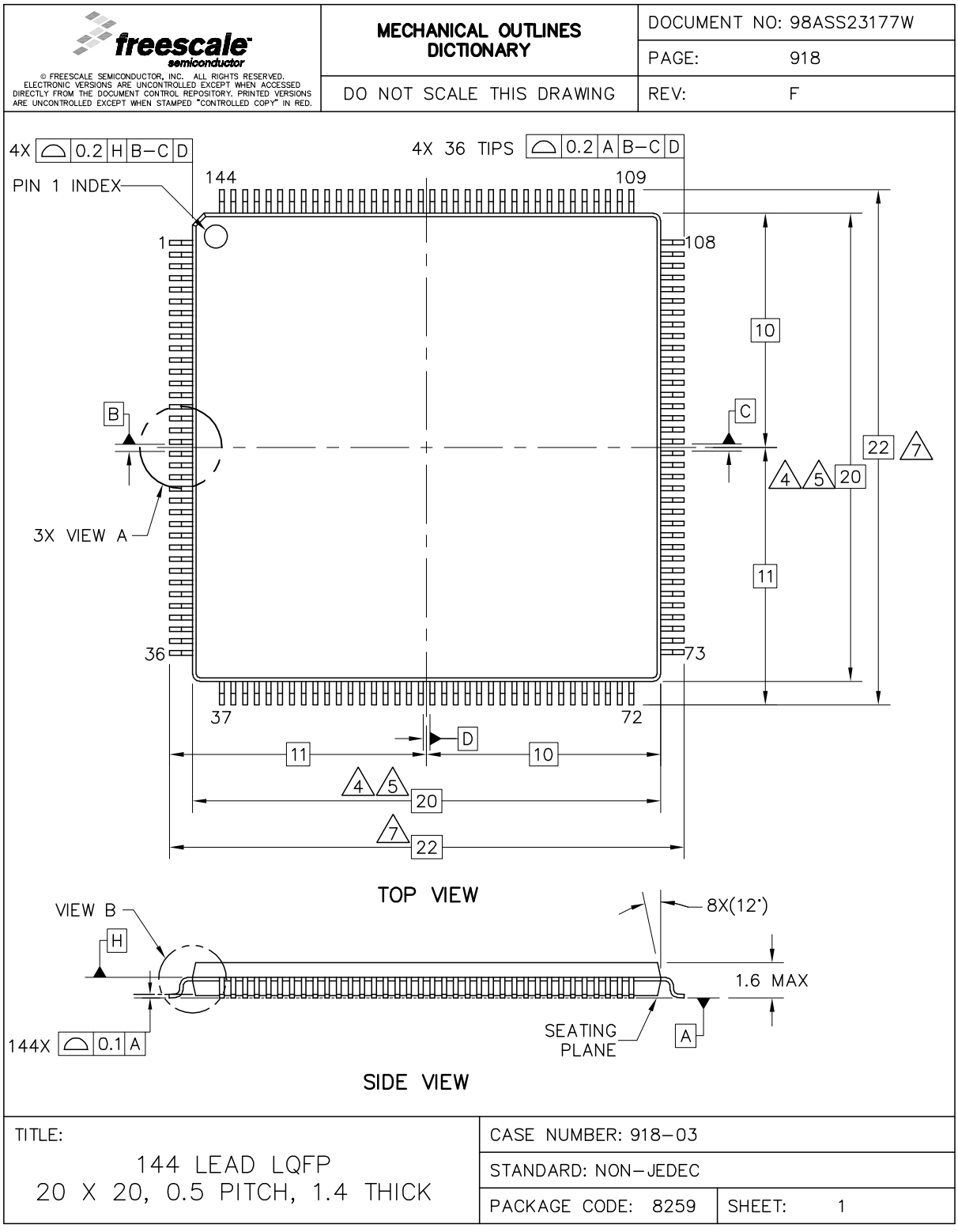


Figure 30. 144 LQFP package mechanical drawing (part 1)

6 Ordering information

Table 42 shows the orderable part numbers for the MPC5634M series.

Table 42. Orderable part number summary

Part Number	Flash/SRAM (Kbytes)	Package	Speed (MHz)
SPC5632MF2MLQ60	768 / 48	144 LQFP Pb-free	60
SPC5632MF2MLQ40	768 / 48	144 LQFP Pb-free	40
SPC5633MF2MMG80	1024 / 64	208 MAPBGA Pb-free	80
SPC5633MF2MLU80	1024 / 64	176 LQFP Pb-free	80
SPC5633MF2MLQ80	1024 / 64	144 LQFP Pb-free	80
SPC5633MF2MMG60	1024 / 64	208 MAPBGA Pb-free	60
SPC5633MF2MLU60	1024 / 64	176 LQFP Pb-free	60
SPC5633MF2MLQ60	1024 / 64	144 LQFP Pb-free	60
SPC5633MF2MLQ40	1024 / 64	144 LQFP Pb-free	40
SPC5634MF2MMG80	1536 / 94	208 MAPBGA Pb-free	80
SPC5634MF2MLU80	1536 / 94	176 LQFP Pb-free	80
SPC5634MF2MLQ80	1536 / 94	144 LQFP Pb-free	80
SPC5634MF2MMG60	1536 / 94	208 MAPBGA Pb-free	60
SPC5634MF2MLU60	1536 / 94	176 LQFP Pb-free	60
SPC5634MF2MLQ60	1536 / 94	144 LQFP Pb-free	60
SPC563M60L3CPBY			
SPC563M60L3CPAY			